

PATENT

IN THE U.S. PATENT AND TRADEMARK OFFICE

In re application of: Yumi SAITO et al.

Conf.:

Appl. No.:

Group:

Filed:

February 10, 2004

Examiner:

Title:

EVALUATION WIRING PATTERN AND EVALUATION
METHOD FOR EVALUATING RELIABILITY OF
SEMICONDUCTOR DEVICE, AND SEMICONDUCTOR
DEVICE HAVING THE SAME PATTERN

PRELIMINARY AMENDMENT

Assistant Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

February 10, 2004

Sir:

The following preliminary amendments and remarks are respectfully submitted in connection with the above-identified application.

Amendments to the Specification begin on page 2 of this paper.

Remarks begin on page 3 of this paper.

An **Appendix** is attached following the signature page of this paper.